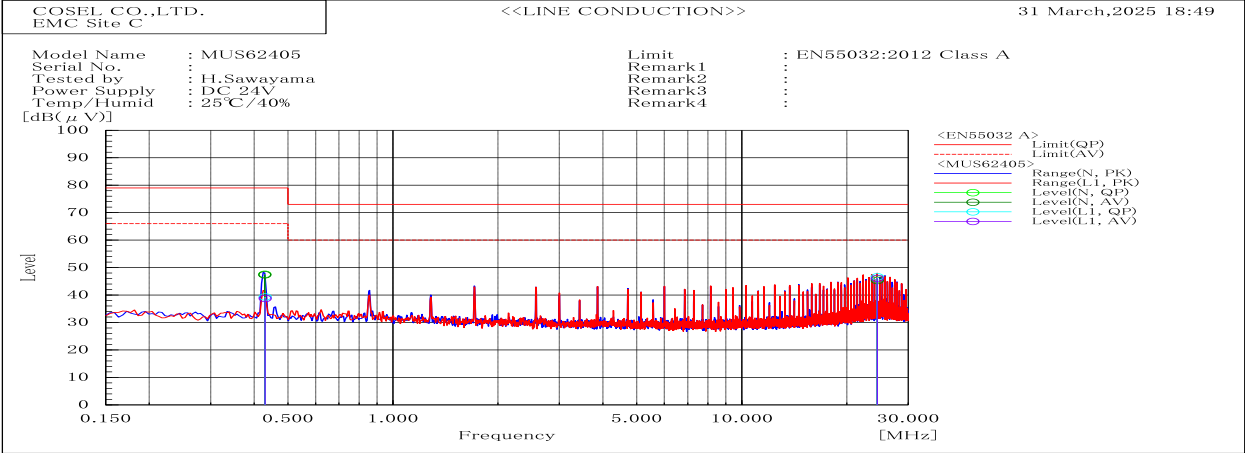
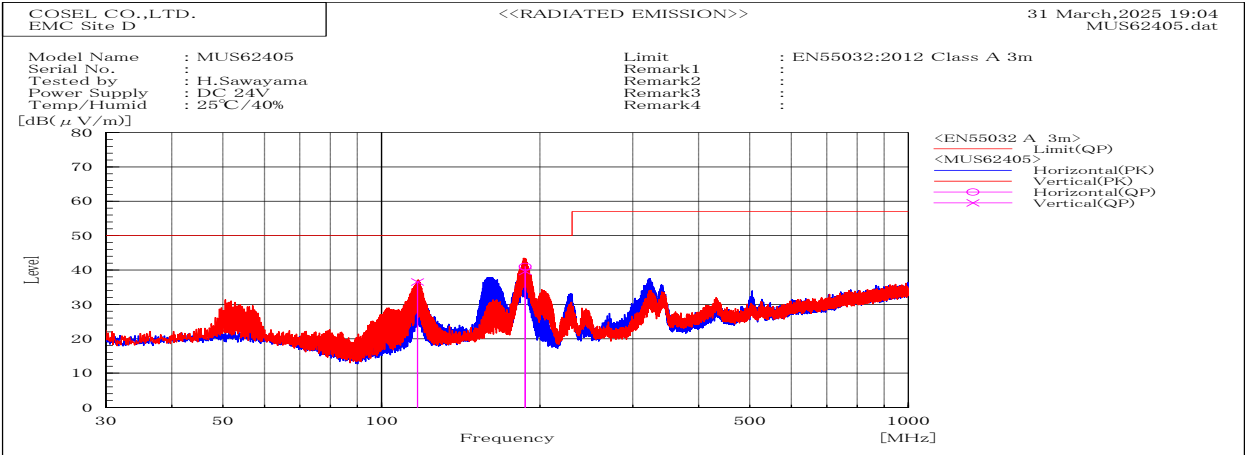


DATA SHEET		Date	31-Mar-25
Model	MUS62405	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	H.Sawayama



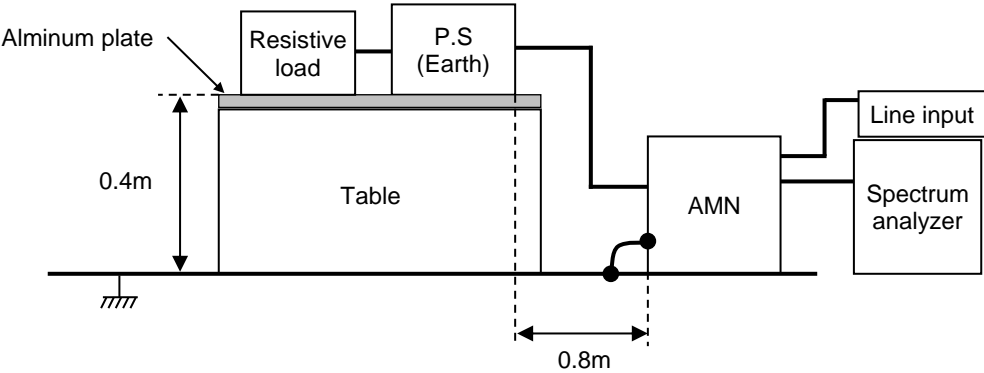
Frequency MHz	Line	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
0.43	L1	39.3	38.8	79	66	39.7	27.2	Pass	
24.464	L1	46.6	46	73	60	26.4	14	Pass	
0.429	N	47.6	47.4	79	66	31.4	18.6	Pass	



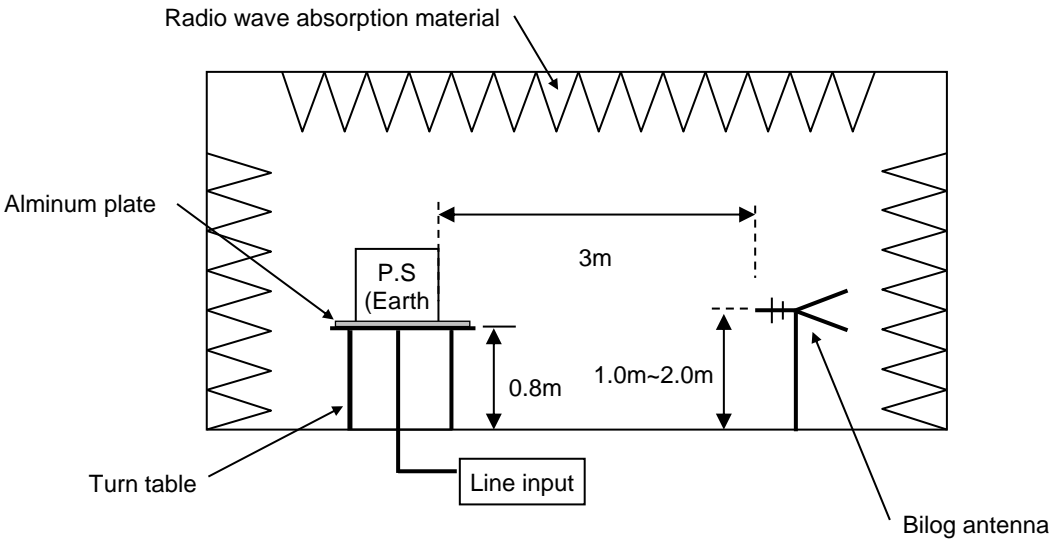
Frequency MHz	Polarization	Stability	Level dB(μV/m)		Limit dB(μV/m)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	QP						
187.454	V	Stable	39.6	50	10.4	Pass	100	0		
187.466	H	Stable	41	50	9	Pass	199.7	171.9		
117.098	V	Stable	36.5	50	13.5	Pass	149	130.3		

DATA SHEET		Date	31-Mar-25
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	H.Sawayama

1. Line conduction



2. Radiated emission



Conditions

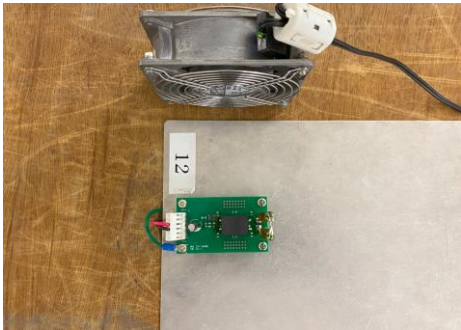
Test : EMI
Model Name: MUS6□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

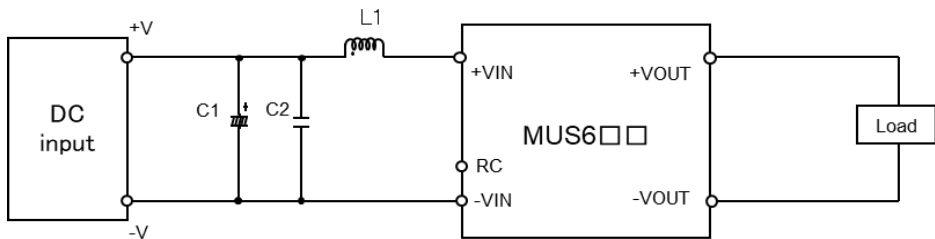


Fig.1 MUS6□□ Testing circuitry

C1 :	MUS605□	16V 220 μ F	Electric capacitor (UPWseries NICHICON)
	MUS612□	50V 100 μ F	Electric capacitor (UPWseries NICHICON)
	MUS624□	—	
	MUS648□	—	
C2 :	MUS605□	16V 22 μ F	Ceramic capacitor (GRM31CC71C226M MURATA MANUFACTURING)
	MUS612□	25V 10 μ F	Ceramic capacitor (CM316X7R106K25AT KYOCERA)
	MUS624□	50V 4.7 μ F	Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING)
	MUS648□	100V 2.2 μ F	Ceramic capacitor (C3216X7S2A225KT TDK)
L1 :	MUS605□	6500mA 1.5 μ H	Inductor(LQH5BPN1R5N38 MURATA MANUFACTURING)
	MUS612□	5000mA 2.2 μ H	Inductor(LQH5BPN2R2N38 MURATA MANUFACTURING)
	MUS624□	2600mA 10 μ H	Inductor(LQH5BPN100M38 MURATA MANUFACTURING)
	MUS648□	1600mA 22 μ H	Inductor(LQH5BPN220M38 MURATA MANUFACTURING)